Bone contour and bone structure determination

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Abstract of **DE 19853965 (A1)**

The method involves using an X-ray system with an X-ray image recording system for the detection of digital X-ray images, and a computer arrangement for determining relevant bone contours and bone structures, especially the passage from cortical to spongy bone contour. At least one first and one second digital X-ray image are recorded by using X-ray radiation of different energy spectra, and a subtraction image is derived through digital subtraction of both images. A contour image is produced through mathematical processing of the subtraction image, to determine the bone contours under application of a computer-based contour recognition method. The contour image is used for the planning and/or selection of the artificial limb implant.